

TECHNICAL SPEC FOR Overlay measurement system

System Model:

Soluris IVS 130

Wafer size: 6 and 8 inch

SECS/GEM: YES

SMIF: NO

Auto template illumination: YES

FSF and edge contrast focus systems: Yes

Laser focus system: NO

Handler: wafer robot cybeq

Pre-aligner, YES

Cassette stations: 3

Asyst SMIF indexers: no

Vintage: 2001

Missing parts: none

Defected parts: none